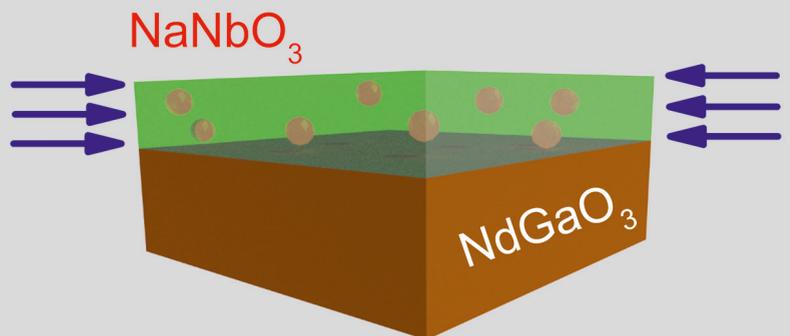
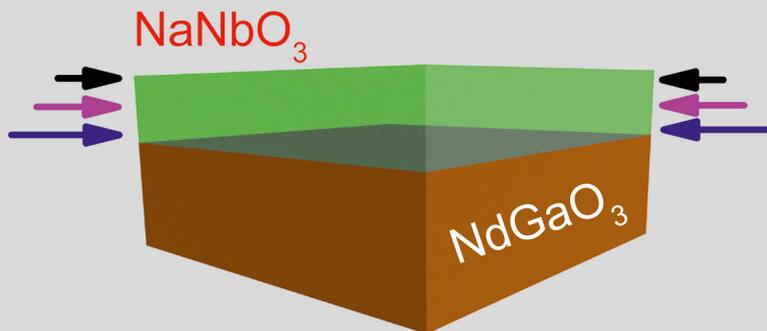


# Manipulating the Structural and Electronic Properties of Epitaxial $\text{NaNbO}_3$ Films via Strain and Stoichiometry

Biya Cai



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